Special Issue

Deep Learning and Machine Learning in Biomedical Signal and Image Processing

Message from the Guest Editor

Machine learning (ML) is an exploratory field dedicated to understanding and building how to learn as well as how to use data to improve the performance of a set of tasks. Among machine learning methods, deep learning (DL) is defined as a set of machine learning algorithms that attempt high-level abstraction through a combination of several nonlinear transformation methods. In particular, the recent development of deep learning using advanced techniques for deep learningbased biomedical image and signal processing has become a field that is being actively studied in medicine and academia. This Special Issue is concerned with biomedical signal processing (ECG, EEG, EMG, PPG, BCG etc.), biomedical image processing (MRI, CT, PET, X-ray etc.), disease diagnosis, biometrics, and biomedical analysis based on deep learning and machine learning

Guest Editor

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